AMENDMENTS TO THE SPECIFICATION

Page 1, lines 12-20

When carrying out a function test on a test device, a semiconductor test apparatus applies a ~~vary~~ very large quantity of measurement input data to the test device in the time axis direction, and it is determined whether or not the output data that is output corresponding to this ~~measured~~ measurement input data matches the measurement expectation data set in advance.

In addition, the semiconductor test apparatus determines that the test device is normal in the case that all of the measurement expectation data, which corresponds to the very large volume of ~~measured~~ measurement input data applied to the test device, agrees with the output data (measurement result data) from the test device.

Page 1, line 25 to Page 2, line 3

The data log system unit in the semiconductor measuring device sequentially records in real time the ~~measured~~ measurement input data of the function test and the ~~measured~~ measurement result data or the like during the measurement of the test device.

Page 2, lines 16-19

In the expected ~~value~~ data generating unit 103, the measurement expectation data SP corresponding to the measurement input conditions mentioned above is generated based on the set measurement conditions mentioned above, and output to the determination unit 104 and the data log system unit 106.

Page 8, lines 3-15

The semiconductor test apparatus of the present invention is characterized in providing an input data generating unit that generates the ~~measured~~ measurement data applied

to the test device based on the input measurement conditions, an expected data generating unit that generates expected data based on the measurement conditions, a determination unit that compares the measurement result data that the test device outputs to the expected data based on the measurement data, determines whether the function of the device is a pass or failure, and outputs the determination result data as the determination result, and a data log system unit that writes into the log memory in a time sequence the associated data that includes the determination result data, measurement result data, measurement expectation data, and measurement input data, wherein the data log system unit writes this associated data into the log memory for a predetermined period even after any of the associated data or the address of the log memory satisfy the preset write termination conditions that terminate the writing.

Page 14, lines 19-24

This means that, as shown in Fig. 4, the data log system unit 16 records by writing in the area of the log memory address "0" (the head address) of the internal log memory the data associated ~~the measurement of~~ with the measurements comprising the input data SI, the measurement result data SO, the measurement expectation data SP, and the measurement determination data SR that correspond to the initial time unit (step S45).

Page 15, lines 18-22

In addition, in step 46, in the case that the set write termination conditions are determined to have been satisfied, the data log system unit 16 determines whether or not the value of the write extension counter is "0", and in the case that the value of the write extension counter is "0", advances the processing to step 51, or in the case that the value of the write extension counter is not "0", advances the processing to step S48 ~~(step 47)~~.